

Laboratory **Sophisticated Test and Instrumentation Centre (STIC), Cochin University Campus, Thrikkakara, Kochi, Kerala**

Accreditation Standard **ISO/IEC 17025: 2005**

Certificate Number **CC-2326**

Page **1 of 15**

Validity **23.11.2018 to 22.11.2020**

Last Amended on **-**

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ( $\pm$ )	Remarks
<b><u>ELECTRO-TECHNICAL CALIBRATION</u></b>				
<b>I.</b>	<b>SOURCE</b>			
1.	DC Voltage <sup>s</sup>	0.1 mV to 1 mV 1 mV to 100 mV 100 mV to 10 V 10 V to 1000 V	3.5 % to 0.36 % 0.36 % to 0.01 % 0.01 % to 0.006 % 0.006 % to 0.007 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method
		100 $\mu$ A to 10 mA 10 mA to 100 mA 100 mA to 1 A 1 A to 20 A	0.041 % to 0.015 % 0.015 % to 0.016 % 0.016 % to 0.055 % 0.055 % to 0.1 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method
		20 A to 1000 A	0.4 % to 0.32 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A with 10/50 Turn Current Coil
3.	AC Voltage <sup>s</sup>	<b>10 Hz to 10 kHz</b> 10 mV to 100 mV 100 mV to 1 V 1 V to 100 V  <b>10 kHz to 100 kHz</b> 10 mV to 100 mV 100 mV to 1 V 1 V to 100 V  <b>45 Hz to 10 kHz</b> 100 V to 1000 V	0.42 % to 0.075 % 0.075 % to 0.047 % 0.047 % to 0.10 %  0.38 % to 0.48 % 0.075 % to 0.30 % 0.047 % to 0.10 %  0.063 % to 0.11 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method
4.	AC Current <sup>s</sup>	<b>50 Hz to 1 kHz</b> 100 $\mu$ A to 100 mA 100 mA to 1 A 1 A to 20 A	0.27 % to 0.09 % 0.09 % to 0.13 % 0.13 % to 0.37 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method

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**Accreditation Standard**    **ISO/IEC 17025: 2005**

**Certificate Number**        **CC-2326**                                      **Page**        **2 of 15**

**Validity**                        **23.11.2018 to 22.11.2020**                      **Last Amended on**    **-**

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		<b>1 kHz to 5 kHz</b> 10 mA to 1 A 1 A to 20 A <b>50 Hz</b> 20 A to 1000 A	0.53 % to 0.82 % 0.13 % to 0.77 % 0.41 % to 0.53 %	
		1 mΩ 10 mΩ 100 mΩ to 1 Ω 1 Ω to 10 Ω 10 Ω to 10 MΩ 10 MΩ to 100 MΩ 100 MΩ to 1 GΩ 1 GΩ to 10 GΩ	0.49 % 0.08 % 0.012 % 0.012 % 0.011 % 0.011 % to 0.12 % 0.12 % 0.12 % to 1.67 %	
6.	Frequency <sup>s</sup>	1 Hz to 250 MHz	0.01 % to 0.003 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method
7.	Inductance <sup>s</sup>	<b>1 kHz</b> 1 mH to 10 H	0.63 % to 1.34 %	Using TE1053 Inductance Box by Direct Method
8.	Capacitance <sup>s</sup>	<b>1 kHz</b> 10 pF to 100 μF	1.03 % to 0.49 %	Using TE1053 Inductance Box by Direct Method
9.	DC Power <sup>s</sup>	10 mW to 100 mW 100 mW to 1 kW 1 kW to 18 kW	0.045 % to 0.05 % 0.05 % to 0.09 % 0.09 % to 0.1 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method

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Certificate Number **CC-2326** Page **3 of 15**

Validity **23.11.2018 to 22.11.2020** Last Amended on **-**

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ( $\pm$ )	Remarks
10.	AC Power <sup>s</sup> 1 $\emptyset$	<b>UPF, 50 Hz</b> 10 mW to 1 W 1 W to 10 W 10 W to 100 W 100 W to 13.8 kW	0.18 % to 0.30 % 0.30 % to 0.26 % 0.26 % to 0.18 % 0.18 % to 0.30 %	Using Wavetek 9100/ Fluke 5500A/Fluke 5502A by Direct Method
11.	Phase Angle <sup>s</sup>	<b>50 Hz</b> +/- 180° 0.2 PF to 1 PF	0.1° 0.8 % to 0.1 %	Using Wavetek 9100/ Fluke 5500A/ 5502A by Direct Method
	Oscilloscope AC/DC Voltage <sup>s</sup> (Amplitude)	4 mV to 40 V	3.33 % to 0.33 %	
	Time Base Accuracy	2 ns to 2 s	0.036 % to 0.028 %	
	Band Width	50 kHz to 250 MHz	3.2 % to 5.7 %	
	Temperature Simulation <sup>s</sup>			
	Thermocouple			
	K-Type	(-) 200°C to 1370°C	0.4°C	
	J-Type	(-) 200°C to 1200°C	0.3°C	
	E-Type	(-) 100°C to 1000°C	0.3°C	
	T-Type	(-) 250°C to 400°C	0.2°C	
	N-Type	(-) 200°C to 1300°C	0.4°C	
	R-Type	0°C to 1760°C	0.8°C	
	S-Type	0°C to 1760°C	1.0°C	
	B-Type	600°C to 1820°C	0.9°C	
	RTD – Pt 385, 100 $\Omega$	(-) 200°C to 800°C	0.10°C	
	Temperature Simulation*			
	Thermocouple			
	K-Type	(-) 200°C to 1370°C	0.4°C	
	J-Type	(-) 200°C to 1200°C	0.3°C	
	E-Type	(-) 100°C to 1000°C	0.3°C	
	T-Type	(-) 250°C to 400°C	0.2°C	
	N-Type	(-) 200°C to 1300°C	0.4°C	
	R-Type	0°C to 1760°C	0.8°C	
	S-Type	0°C to 1760°C	1.0°C	
	B-Type	600°C to 1820°C	0.9°C	
	RTD – Pt 385, 100 $\Omega$	(-) 200°C to 800°C	0.10°C	

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Accreditation Standard ISO/IEC 17025: 2005

Certificate Number

CC-2326

Page 4 of 15

Validity

23.11.2018 to 22.11.2020

Last Amended on -

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ( $\pm$ )	Remarks
II.	<b>MEASURE</b>			
1.	DC Voltage <sup>§</sup>	0.1 mV to 1 mV 1 mV to 100 mV 100 mV to 1000 V	0.13 % to 0.014 % 0.014 % to 0.001 % 0.001 %	Using Fluke 8508A by Direct Method
2.	DC Current <sup>§</sup>	100 $\mu$ A to 10 mA 10 mA to 100 mA 100 mA to 1 A 1 A to 20 A	0.003 % 0.003 % to 0.007 % 0.007 % to 0.024 % 0.024 % to 0.05 %	Using Fluke 8508A by Direct Method
		<b>10 Hz to 1 kHz</b> 1 mV to 100 mV 100 mV to 1 V 1 V to 100 V	0.37 % to 0.01 % 0.01 % to 0.005 % 0.005 %	
		<b>1 kHz to 100 kHz</b> 1 mV to 100 mV 100 mV to 1 V 1 V to 100 V	0.25 % to 0.03 % 0.03 % to 0.009 % 0.009 % to 0.027 %	
		<b>100 kHz to 500 kHz</b> 1 mV to 100 mV 100 mV to 1 V	1.18 % to 0.06 % 0.06 % to 0.035 %	
		<b>500 kHz to 1 MHz</b> 5 mV to 1 V	1.2 % to 0.12 %	
		<b>45 Hz to 10 kHz</b> 100 V to 1000 V	0.007 % to 0.013 %	
		<b>10 Hz to 50 Hz</b> 1 mA to 1 A	0.037 % to 0.013 %	
		<b>50 Hz to 1 kHz</b> 100 $\mu$ A to 1 A 1 A to 10 A 10 A to 20 A	0.06 % to 0.013 % 0.013 % to 0.016 % 0.016 % to 0.031 %	
		<b>1 kHz to 10 kHz</b> 10 mA to 1 A	0.012 % to 0.014 %	

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**Certificate Number**        **CC-2326**                                      **Page**        **5 of 15**

**Validity**                        **23.11.2018 to 22.11.2020**                                      **Last Amended on** -

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		<b>1 kHz to 5 kHz</b> 1 A to 10 A	0.014 % to 0.02 %	
		<b>45 Hz to 5 kHz</b> 10 A to 20 A	0.02% to 0.034%	
<b>5.</b>	DC Resistance <sup>\$</sup>	1m $\Omega$ to 1 $\Omega$ 1 $\Omega$ to 10k $\Omega$ 10k $\Omega$ to 1M $\Omega$ 1 M $\Omega$ to 100M $\Omega$ 100M $\Omega$ to 1G $\Omega$ 1G $\Omega$ to 10G $\Omega$	0.46% to 0.002% 0.002% to 0.001% 0.001% to 0.002% 0.002% to 0.01% 0.01% to 0.04% 0.04% to 0.30%	Using Fluke 8508A by Direct Method
<b>6.</b>	Frequency <sup>\$</sup>	1 Hz to 1 GHz	0.001 %	Using Philips FC2130U by Direct Method
<b>7.</b>	Inductance <sup>\$</sup>	<b>1 kHz</b> 1 mH to 10 H	0.1 % to 0.13 %	Using Agilent 4263B by Direct Method
<b>8.</b>	Capacitance <sup>\$</sup>	<b>1 kHz</b> 10 pF to 100 $\mu$ F	0.16 % to 0.34 %	Using Agilent 4263B by Direct Method
<b>9.</b>	Phase Angle <sup>\$</sup>	<b>50 Hz</b> +/- 180° 0.2 PF to 1 PF	0.06 ° 0.15 % to 0.02 %	Using Clarke Hess 6000A by Direct Method
<b>10.</b>	RF Power <sup>\$</sup>	<b>10MHz to 1GHz</b> (-) 30 dBm to 13 dBm	5.2% to 4.3%	Using Agilent E4418B & E9300H by Direct Method
		10 s to 300 s	1.04 % to 0.068 %	
		300 s to 900 s	0.068 % to 0.061 %	
		900 s to 1800 s	0.061 % to 0.059 %	

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**Certificate Number** CC-2326

**Page** 6 of 15

**Validity** 23.11.2018 to 22.11.2020

**Last Amended on** -

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ( $\pm$ )	Remarks
12.	Temperature Simulation <sup>s</sup>			Using Fluke 1529 (Chub E4) by Direct Method
	Thermocouple			
	K-Type	(-) 200 °C to 1370 °C	0.17 °C	
	J-Type	(-) 200 °C to 1200 °C	0.12 °C	
	E-Type	(-) 250 °C to 1000 °C	0.29 °C to 0.08 °C	
	T-Type	(-) 250 °C to 400 °C	0.13 °C to 0.12 °C	
	N-Type	(-) 200 °C to 1300 °C	0.35 °C	
	R-Type	0 °C to 1760 °C	0.58 °C	
	S-Type	0 °C to 1760 °C	0.70 °C	
B-Type	600 °C to 1820 °C	0.71 °C to 0.69 °C		
	RTD - Pt 385, 100 ohm	(-) 200 °C to 800 °C	0.01 °C to 0.03 °C	
13.	Time Interval*	10 s to 300 s	1.04 % to 0.068 %	Using Philips FC2130U Frequency Counter Wavetek 9100/Fluke 5500A/5502A by Time Totalisation Method
		300s to 900s	0.068 % to 0.061 %	
		900s to 1800s	0.061 % to 0.059 %	
	Temperature Simulation*			
	Thermocouple			
	K-Type	(-) 200°C to 1370°C	0.17°C	
	J-Type	(-) 200°C to 1200°C	0.13°C to 0.12°C	
	E-Type	(-) 250°C to 1000°C	0.29°C to 0.08°C	
	T-Type	(-) 250°C to 400°C	0.12°C to 0.13°C	
	N-Type	(-) 200°C to 1300°C	0.35°C	
	R-Type	0°C to 1760°C	0.58°C	
	S-Type	0°C to 1760°C	0.70°C	
B-Type	600°C to 1820°C	0.71°C to 0.69°C		
	RTD – Pt 385, 100ohm	(-) 200°C to 800°C	0.01°C to 0.03°C	

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Accreditation Standard ISO/IEC 17025: 2005

Certificate Number

CC-2326

Page 7 of 15

Validity

23.11.2018 to 22.11.2020

Last Amended on -

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<b><u>MECHANICAL CALIBRATION</u></b>				
<b>1. DIMENSION (BASIC MEASURING INSTRUMENT, GAUGE ETC.)</b>				
1.	Calipers <sup>§</sup> LC.: 0.01 mm LC.: 0.02 mm L.C.: 0.02 mm	0 to 300 mm 0 to 600 mm 0 to 1000 mm	9 $\mu$ m 16 $\mu$ m 22 $\mu$ m	Using 'K' Grade Gauge Blocks
2.	External Micrometer / Digimatic Micrometer/ Blade/Groove/Ball Micrometer <sup>§</sup> L.C.: 0.001 mm L.C.: 0.01 mm	0 to 100 mm 0 to 150 mm	6 $\mu$ m 15 $\mu$ m	Using 'K' Grade Gauge Blocks
3.	Depth Micrometer / Digital/Analog <sup>§</sup> L.C.: 0.01 mm	0 to 300 mm	6 $\mu$ m	Using 'K' Grade Gauge Blocks
4.	Height Gauge Electronic / Analog <sup>§</sup> L.C.: 0.001 mm <sup>Φ</sup>	0 to 1000 mm	12 $\mu$ m	Using 'K' Grade Gauge Blocks
5.	Dial Gauge <sup>§</sup> (Plunger/Lever Type)/ Bore Gauge L.C.: 0.001 mm <sup>Φ</sup>	0 to 25 mm	4 $\mu$ m	Using 'K' Grade Gauge Blocks/Electronic Dial Calibration Tester
6.	Steel Scale <sup>§</sup> L.C.: 0.05 mm <sup>Φ</sup>	1 mm to 1000 mm	0.33 mm	Using Scale & Tape Calibration Unit
7.	Measuring Tape <sup>§</sup>	1 mm to 1000 mm (Multiples of 1000)	0.40 mm 0.40 $\sqrt{L}$ , L in m	Using Scale & Tape Calibration Unit

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Accreditation Standard ISO/IEC 17025: 2005

Certificate Number

CC-2326

Page 8 of 15

Validity

23.11.2018 to 22.11.2020

Last Amended on -

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8.	Dial Thickness Gauge (Dial/Digital) <sup>§</sup> L.C.: 0.001 mm <sup>Φ</sup>	0 to 25 mm	4 $\mu$ m	Using 'K' Grade Gauge Blocks
II.	<b>WEIGHTS</b>			
	Mass/Weights <sup>§</sup> E2 Class & coarser	1 mg 2 mg 5 mg 10 mg 20 mg 50 mg 100 mg 200 mg 500 mg 1 g 2 g 5 g	0.002 mg 0.002 mg 0.002 mg 0.002 mg 0.002 mg 0.002 mg 0.002 mg 0.002 mg 0.003 mg 0.003 mg 0.003 mg 0.004 mg	Using E1 Class Weights & Electronic Weighing Balance 6.1g(0.001mg) as per OIML R111-1
	E2 Class and Coarser	10 g 20 g 50 g 100 g 200 g	0.02 mg 0.02 mg 0.02 mg 0.02 mg 0.05 mg	Using E1 Class Weights & Electronic Weighing Balance 220 g (0.01 mg)
	M1 Class and Coarser	500 g 1 kg 2 kg 5 kg 10 kg 20 kg 40 kg	8.0 mg 10.0 mg 14.4 mg 14.4 mg 23.0 mg 40.0 mg 50.0 mg	Using F1 Class Weights & Mass Comparator 40Kg(10 mg)

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**Certificate Number**             **CC-2326**                                 **Page**         **9 of 15**

**Validity**                                 **23.11.2018 to 22.11.2020**                                 **Last Amended on** -

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<b>III.</b>	<b>WEIGHING SCALE AND BALANCE</b>			
	Electronic Weighing Balance*			
	Class I & coarser	0 to 6.1 g (Readability 0.001 mg) 6 g to 220 g (Readability 0.01 mg)	0.008 mg 0.06 mg	Using E1 Class Standard Weights as per OIML R76-1
	Class II & coarser	5 kg to 40 kg (Readability 0.01 g)	0.07 g	Using F1 Class Standard Weights as per OIML R76-1
<b>2.</b>	GSM Tester*	10 mg to 140 g (Readability 0.01 g)	8.6 mg	Using E1 Class Standard Weights as per Procedure BCP
<b>IV.</b>	<b>VOLUME</b>			
	Volumetric Measures <sup>§</sup>			
	Glass Pipette & Burette	0.1 ml to 250 ml	0.024 ml	Using Electronic weighing balance 220g (Readability 0.01mg) as per ISO 4787
		1 $\mu$ l to 5 $\mu$ l	0.08 $\mu$ l	
		5 $\mu$ l to 50 $\mu$ l	0.10 $\mu$ l	
		20 $\mu$ l to 200 $\mu$ l	0.10 $\mu$ l	
		200 $\mu$ l to 1000 $\mu$ l	0.17 $\mu$ l	
		1000 $\mu$ l to 5000 $\mu$ l	0.20 $\mu$ l	
	Volumetric Flask & Measuring Cylinder	0.1 ml to 10 ml 10 ml to 250 ml 250 ml to 2000 ml	0.02 ml 0.02 ml 0.04 ml	Using Electronic Weighing Balance 220g (Readability 0.01mg) & 40kg(Readability 10mg) as per ISO 4787

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**Accreditation Standard**

**ISO/IEC 17025: 2005**

**Certificate Number**

**CC-2326**

**Page**

**10 of 15**

**Validity**

**23.11.2018 to 22.11.2020**

**Last Amended on -**

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<b>V.</b>	<b>PRESSURE INDICATING DEVICES</b>			
1.	Pneumatic Pressure (Digital / Analog Pressure Gauges, Portable Calibrators, Compound Gauges, Pressure Transmitters with Indicator, Transducers, Pressure Switches, Relief Valves) <sup>§</sup>	0 to 20 bar	0.20% of rdg	Using Budenberg Pressure Calibrator as per DKD-R-6-1
2.	Vacuum (Digital / Analog Vacuum Gauges, Transmitters With Indicator, Portable Calibrators, Transducers, Pressure Switches, Relief Valves) <sup>§</sup>	0 to (-) 0.94 bar	0.002 bar	Using Budenberg Pressure Calibrator as per DKD-R-6-2
3.	Hydraulic Pressure (Digital / Analog Pressure Gauges, Pressure Transmitters with Indicator, Transducers, Pressure Switches, Relief Valves) <sup>*</sup>	0 to 10 bar 10 bar to 200 bar 200 bar to 400 bar	1.2 % of rdg 0.42 % of rdg 0.07 % of rdg	Using Budenberg Pressure Calibrator as per DKD-R-6-1
4.	Pneumatic Pressure (Digital / Analog Pressure Gauges, Pressure	0 to 20 bar	0.28% of rdg	Using Budenberg Pressure Calibrator as per DKD-R-6-1

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**Certificate Number**        **CC-2326**                                      **Page**        **11 of 15**

**Validity**                        **23.11.2018 to 22.11.2020**                                      **Last Amended on** -

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	Transmitters with Indicator, Transducers, Compound Gauges, Pressure Switches) *			
5.	Vacuum (Digital / Analog Vacuum Gauges, Transmitters with Indicator, Transducers) *	0 to (-) 0.94 bar	0.002 bar	Using Budenberg Pressure Calibrator as per DKD-R-6-2.
<b>VI.</b>	<b>ACCERELRATION AND SPEED</b>			
1.	Speed (rpm) Digital/ Analog Tachometer (Non Contact Type) §	60 rpm to 25000 rpm	3 rpm	Using Wave form Generator as per SANAS-TR-45
2.	Speed (rpm) Tachometer/ Centrifuge/Magnetic Stirrer, Motor, Flash Point Apparatus (Contact Type) §	60 rpm to 20000 rpm	3 rpm	Using Non contact Tachometer as per SANAS-TR-45
3.	Speed (rpm) Centrifuge/Magnetic Stirrer, Motor, Flash Point Apparatus, Triple Roll Mill, Mixer, High Speed Motor*	60 rpm to 20000 rpm	2.5 rpm	Using Non contact Tachometer as per SANAS-TR-45

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**Certificate Number** CC-2326 **Page** 12 of 15

**Validity** 23.11.2018 to 22.11.2020 **Last Amended on** -

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<b><u>THERMAL CALIBRATION</u></b>				
<b>I.</b>	<b>TEMPERATURE</b>			
1.	Resistance Thermometers / Thermocouples / Thermistors with/without Temperature Indicators, Temperature Gauges, Digital Thermometers, Temperature Indicator with Sensor of Calibrators, Baths, Incubators (for Non-Medical Applications), Refrigerators, Deep Freezer, Furnaces, Ovens, Chambers etc. <sup>§</sup>	(-) 80 °C to 0 °C 0 to 200 °C 200 °C to 400 °C 400 °C to 660 °C	0.05 °C 0.03 °C 0.14 °C 0.21 °C	Using SPRT / STC, Liquid Bath / Ice Bath / Dry Block Furnace and DMM by Comparison Method
2.	Liquid-in-Glass Thermometers <sup>§</sup>	(-) 80 °C to 200 °C	0.07 °C	Using SPRT / Liquid Bath / Ice Bath / and DMM by Comparison Method
3.	Resistance Thermometers / Thermocouples with/without Indicators, Digital Thermometers, Temperature Indicator with	660 °C to 1200 °C	1.62 °C	Using Standard S-type Thermocouple, Dry Block Furnace and DMM by Comparison Method

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**Certificate Number**        **CC-2326**                                      **Page**      **13 of 15**

**Validity**                        **23.11.2018 to 22.11.2020**                      **Last Amended on** -

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	Sensor of Calibrators, Furnaces etc. \$			
4.	Calibration of Liquid Baths, Dry Blocks, Ovens, Incubators (for Non-Medical Applications), Chambers, Furnaces etc. \$	(-) 80 °C to 50 °C 50 °C to 250 °C	0.4 °C 1.2 °C	Using Multi Position Calibration with PRTs / N Type TC, DMM Mapping method
5.	Thermo – Hygro Meters, RH / Temperature Indicator With Sensor etc. \$	10 °C to 50 °C @ 40 % RH	0.20 °C	Using Humidity/ Temperature Generator, PRT, DMM by Comparison method
6.	Resistance Thermometers / Thermocouples / Thermistors with/ without Temperature Indicators, Temperature Gauges, Digital Thermometers, Temperature Indicator with Sensor of Calibrators, Baths, Incubators (for Non-Medical Applications), Refrigerators, Deep Freezer, Furnaces, Ovens, Chambers etc.*	(-) 80 °C to 0 °C 0 to 200 °C 200 °C to 400 °C 400 °C to 660 °C	0.05 °C 0.03 °C 0.14 °C 0.21 °C	Using SPRT / STC, Liquid Bath / Ice Bath / Dry Block Furnace and DMM by Comparison Method

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Certificate Number **CC-2326** Page **14 of 15**

Validity **23.11.2018 to 22.11.2020** Last Amended on **-**

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability ( $\pm$ )	Remarks
7.	Liquid-in-Glass Thermometers*	(-) 80 °C to 200 °C	0.07 °C	Using SPRT / Liquid Bath / Ice Bath / and DMM by Comparison Method
8.	Resistance Thermometers / Thermocouples with/without Indicators, Digital Thermometers, Temperature Indicator with Sensor of Calibrators, Furnaces etc.*	660 °C to 1200 °C	1.62 °C	Using Standard S-type Thermocouple, Dry Block Furnace and DMM by Comparison method
9.	Calibration of Liquid Baths, Dry Blocks, Ovens, Incubators (for Non-Medical Applications), Chambers, Furnaces etc. *	(-) 80 °C to 50 °C 50 °C to 250 °C 250 °C to 600 °C 600 °C to 900 °C 900 °C to 1200 °C	0.4 °C 1.2 °C 1.8 °C 3.5 °C 4.0 °C	Using PRTs / N Type TC. Multi Position Calibration, DMM by Mapping method
II.	<b>SPECIFIC HEAT &amp; HUMIDITY</b>			
1.	RH Indicators, Digital / Analog Hygrometers, Thermo - Hygro Meters, RH Indicator with Sensor etc.\$	30 % to 90 % (in the temperature range 25 $\pm$ 5°C)	3.8 %	Using Humidity/ Temperature Generator, PRTs (Wet & Dry Method), DMM by Comparison Method

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Program Manager

Laboratory **Sophisticated Test and Instrumentation Centre (STIC), Cochin  
University Campus, Thrikkakara, Kochi, Kerala**

Accreditation Standard **ISO/IEC 17025: 2005**

Certificate Number **CC-2326** Page **15 of 15**

Validity **23.11.2018 to 22.11.2020** Last Amended on **-**

Sl.	Quantity Measured / Instrument	Range/Frequency	*Calibration Measurement Capability (±)	Remarks
2.	Relative Humidity Indicator of Chamber*	30 % to 95 % (in the temperature range 25±5°C	2.6 %	Using PRTs (Wet & Dry method), DMM by Comparison Method

\* Measurement Capability is expressed as an uncertainty (±) at a confidence probability of 95%

§Only in Permanent Laboratory

\*Only for Site Calibration

Ⓟ Laboratory can also calibrate instruments/devices of coarser resolution / least count within the accredited range using same reference standard/ master equipment under the scope of accreditation.